

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination EBIHARA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0162010	08-2004	Ohno et al.	451/041
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11114793 A	04-1999	Japan		B24B 21/00
	O	JP 2000182237 A	06-2000	Japan	OKUMURA et al.	G11B 05/84
	P	JP 2001179595 A	07-2001	Japan	KIYOMURA et al.	B24B 29/00
	Q	JP 2001179594 A	07-2001	Japan	TOMIOKA et al.	B24B 29/00
	R	JP 2001179588 A	07-2001	Japan	KIYOMURA et al.	B24B 21/00
	S	JP 2002331465 A	11-2002	Japan	TOMIOKA et al.	B24D 11/00
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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